



Title of Change:	Adding King Yuan Electronics Corp Taiwan (KYE) as an additional Final Test Location												
Proposed first ship date:	24 November 2015 <i>or earlier after customer approval</i>												
Contact information:	Contact your local ON Semiconductor Sales Office or Tamara Olney <Tamara.Olney@onsemi.com>												
Samples:	Contact your local ON Semiconductor Sales Office												
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office												
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>.												
Change Part Identification:	Affected products will be identified with date code												
Change category:	<input type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input checked="" type="checkbox"/> Test Change <input type="checkbox"/> Other _____												
Change Sub-Category(s): <input checked="" type="checkbox"/> Manufacturing Site Change/Addition <input type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Other: _____													
Sites Affected: <input type="checkbox"/> All site(s) <input type="checkbox"/> not applicable <input type="checkbox"/> ON Semiconductor site(s) : <div style="text-align: right;"><input checked="" type="checkbox"/> External Foundry/Subcon site(s) King Yuan Electronics Co., Ltd.</div>													
Description and Purpose: Adding KYEC as an additional test site to increase ON Semiconductor test capacity. This change does not affect the product form, fit, or function. KYEC is a qualified test house for ON Semiconductor.													
Qualification Data Summary: <u>Qual requirements:</u> Qualification was performed per ON Semiconductor 12MID07-0107. This includes repeatability tests, correlation of parametric measurements, and yield/bin correlation. Full parametric correlation was performed and for every test the shift was evaluated as per the below table: <table border="1" style="width: 100%;"> <tr> <td>$dmean = abs(mean(ref) - mean(qual))$</td><td></td></tr> <tr> <td>$d\sigma = 0$</td><td>if $\sigma(qual) < \sigma(ref)$</td></tr> <tr> <td>$d\sigma = \sigma(qual) - \sigma(ref)$</td><td>if $\sigma(qual) > \sigma(ref)$</td></tr> <tr> <td>$shift = dmean + 4 * d\sigma$</td><td></td></tr> <tr> <td>If $shift < \max(5\% \text{ specwidth}, 6 * \sigma(ref))$ then correlation is OK for this test,</td><td>else correlation is NOK for this test</td></tr> </table>				$dmean = abs(mean(ref) - mean(qual))$		$d\sigma = 0$	if $\sigma(qual) < \sigma(ref)$	$d\sigma = \sigma(qual) - \sigma(ref)$	if $\sigma(qual) > \sigma(ref)$	$shift = dmean + 4 * d\sigma$		If $shift < \max(5\% \text{ specwidth}, 6 * \sigma(ref))$ then correlation is OK for this test,	else correlation is NOK for this test
$dmean = abs(mean(ref) - mean(qual))$													
$d\sigma = 0$	if $\sigma(qual) < \sigma(ref)$												
$d\sigma = \sigma(qual) - \sigma(ref)$	if $\sigma(qual) > \sigma(ref)$												
$shift = dmean + 4 * d\sigma$													
If $shift < \max(5\% \text{ specwidth}, 6 * \sigma(ref))$ then correlation is OK for this test,	else correlation is NOK for this test												
Note: Summary: All parameters pass the correlation requirements. For reference, attached is the detailed correlation report for each device. To access file attachments on pdf copy of PCN, please be guided by the steps below: 1. Download pdf copy of the PCN to your computer 2. Open the downloaded pdf copy of the PCN 3. Click on the paper clip icon available on the menu provided in the left/bottom portion of the screen to reveal the Attachment field 4. Then click on the attached file/s													
Electrical Characteristic Summary: Electrical characteristics are not impacted.													
List of Affected Standard Parts:													
Part Number		Qualification Vehicle											
NCS37010DBRG		21579-004											